Supplementary Information

Vertically-stacked monolithic multilayer perovskite photodetectors for color-filter-free imaging

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Contents

Supplementary Note 1. Perovskite sensor structure
1.1 Red color detector stack
1.2 Green color detector Stack
1.3 Blue color detector stack
Supplementary Table 1. Complete sensor structure 1
Supplementary Table 2. Complete sensor structure 2
Supplementary Note 2. Alternative technologies promising for monolithic stacked detector fabrication
2.1 III-V materials for integration in vertically stacked photodetectors
2.2 Organic photodetectors
Supplementary Note 3. Procedure for evaluation of color accuracy of optical sensor
Supplementary Fig. 1 Atomic force microscopy images of perovskite layers
Supplementary Fig. 2 External Quantum Efficiency of a stacked detector with structure 1 19
Supplementary Fig. 3 3 dB bandwidth of the R, G, and B single color detectors
Supplementary Fig. 4 Capacitance vs frequency measurements of stacked photodetectors 20
Supplementary Fig. 5 Emission spectra of RGB channels emitted by LC-10W diode 20
Supplementary Fig. 6 Comparative performance of red detectors with 30 nm and 100 nm better gold electrode
bottom gold electrode
Supplementary Table 4. Comparative detectivity metrics of broadband perovskite, organic, silicon, and stacked perovskite photodetectors
Supplementary References 22

Supplementary Note 1. Perovskite sensor structure

1.1 Red color detector stack

In our approach to developing a stacked perovskite layer, we aimed for methodologies designed for seamless transfer to CMOS-compatible processing. We selected vapor-phase perovskite deposition to facilitate deposition on textured and uneven surfaces, which may be essential for further application on CMOS chips and avoid problems with the dissolution of perovskites by the subsequent layers. We avoided thick dielectric spacers, such as polymer films and parylene, to maintain a relatively thin total sensor thickness. This is vital for future developments of the practical sensor arrays, which will require lithographic etching and integrating via connectors onto CMOS chips.

The deposition process begins with dielectric/Au/dielectric electrodes, utilizing MoO₃ as an adhesive layer beneath the gold and as a buffer layer. This reflective Au electrode was used to enhance the light absorption in the red detection layer. We discovered that keeping the gold layer thin (30 nm) was essential for achieving leak-free detectors, as devices with 100nm gold layers exhibited significantly higher leakage (Supplementary Fig. 6). In general, these stacked structures are very demanding of having sharp-edge-free bottom electrodes. We chose MAPbI₂Br for its ease of use and reproducibility as the perovskite composition. The structure was completed with a C60/ZnO/ITO layer, employing ZnO as a protective layer to mitigate sputter damage on the perovskite/ETL stack. Continuing the fabrication, we deposited dielectric stacks. It was noted that while the main ITO electrode surface was sufficiently protective against perovskite decomposition during processing, areas not covered by ITO (deposited through a shadow mask) might react with subsequent perovskite layer stacks. Initially, a combination of SnO₂ and SiO₂ was included as protective and dielectric layers. The SnO₂ layer (deposited with pulsed DC sputtering) was later selected due to observed degradation and bleaching of perovskite when SiO₂ was sputtered (RF) directly onto areas of the perovskite substrate without ITO coverage.

1.2 Green color detector Stack

The green stack's fabrication commenced with the deposition of the ITO electrode and a SnO₂/C60 ETL stack. We selected CsPbBr₂I as a stable inorganic perovskite for the perovskite layer. We encountered low batch-to-batch reproducibility while experimenting with the thermally evaporated MAPbBr_{2.5}I_{0.5} composition. Given the entire sensor fabrication process could extend

up to 3-4 weeks, maintaining high reproducibility was deemed crucial, leading to a focus on inorganic perovskites. A composite HTL comprising TCTA/MoO₃ and an additional AZO nanocrystal buffer layer was used to minimize the sputtering damage on the green cell. The TCTA layer was chosen to maintain vapor deposition for the entire stack and its high glass transition temperature¹, crucial for the thermal stability of the cell upon deposition of the third stack.

1.3 Blue color detector stack

The fabrication of the blue stack began with the deposition of a 2PACz and NiO composite layer. The initial 2PACz coating provided a hole-selective interface coating for the edges of the bottom ITO electrode, addressing the potential non-conformality of NiO NC coating on the sharp electrode edges. The CsPbClBr₂ layer was used as the absorber layer due to its high stability. Although we experimented with MAPbBr_{1.5}Cl_{1.5} as an absorber layer, we could not achieve an EQE higher than 20% with this composition. Notably, we achieved an 81% EQE with high-performance solution-processed FAPbBr_{1.5}Cl_{1.5} detectors. However, the evaporation of FABr or FACl precursors in our PVD chamber proved challenging. To maintain consistency with PVD-processed stacks, we decided against incorporating any solution-processed perovskite layers in the stack, further complicated by issues of perovskite dissolution in the bottom layers when a solution-based composition was used.

Supplementary Table 1. Complete sensor structure 1. Layers are deposited in order from layer 1, beginning with a 25x25 mm soda lime glass substrate.

	Layer	Nominal	Deposition method	Role
		thickness (nm)		
1	MoO ₃	15	Thermal evaporation	Adhesion
2	Gold	30	Thermal evaporation	Electrode
3	MoO ₃	30	Thermal evaporation	Buffer
4	2PACz	<2	Spincoating	Hole-selective
5	MAPbBrI ₂	450	Thermal evaporation	Absorber
6	C60	20	Thermal evaporation	Electron-transport

7	ZnO	40	Spincoating	Buffer
8	ITO	180	Sputtering	Electrode
9	SnO ₂	40	Sputtering	Protective
10	SiO ₂	200	Sputtering	Dielectric
11	ITO	180	Sputtering	Electrode
12	SnO ₂	40	Sputtering	Electron-transport
13	C60	5	Thermal evaporation	Electron-transport
14	CsPbBr ₂ I	300	Thermal evaporation	Absorber
15	TCTA	15	Thermal evaporation	Hole-transport
16	MoO ₃	30	Thermal evaporation	Buffer
17	AZO	40	Spincoating	Buffer
18	ITO	140	Sputtering	Electrode
19	SnO ₂	40	Sputtering	Protective
20	SiO ₂	200	Sputtering	Dielectric
21	ITO	100	Sputtering	Electrode
22	2PACz	<2	Spincoating	Hole selective
23	NiO	30	Spincoating	Hole transport
24	TCTA	5	Thermal evaporation	Hole transport
25	CsPbBr ₂ Cl	200	Thermal evaporation	Absorber
26	PCBM	~40	Spincoating	Electron-transport
27	C60	5	Thermal evaporation	Electron-transport
28	ZnO	40	Spincoating	Buffer
29	ITO	120	Sputtering	Electrode

Supplementary Table 2. Complete sensor structure 2. Layers are deposited in order from layer

1, beginning with a 25x25 mm soda lime glass substrate.

Layer	Nominal	Deposition method	Role
	thickness (nm)		

1	MoO ₃	15	Thermal evaporation	Adhesion
2	Gold	30	Thermal evaporation	Electrode
3	MoO ₃	30	Thermal evaporation	Buffer
4	2PACz	<2	Spincoating	Hole-selective
5	MAPbBrI ₂	450	Thermal evaporation	Absorber
6	C60	40	Thermal evaporation	Electron-transport
7	ZnO	40	Spincoating	Buffer
8	SnO ₂	40	ALD	Buffer
9	ITO	180	Sputtering	Electrode
10	SnO ₂	40	Sputtering	Electron-transport
11	C60	5	Thermal evaporation	Electron-transport
12	CsPbBr ₂ I	300	Thermal evaporation	Absorber
13	TCTA	15	Thermal evaporation	Hole-transport
14	MoO ₃	30	Thermal evaporation	Buffer
15	ITO	100	Sputtering	Electrode
16	2PACz	<2	Spincoating	Hole selective
17	NiO	30	Spincoating	Hole transport
18	TCTA	5	Thermal evaporation	Hole transport
19	CsPbBr ₂ Cl	400	Thermal evaporation	Absorber
20	C60	20	Thermal evaporation	Electron-transport
21	ВСР	8	Thermal evaporation	Buffer
22	Ag	1	Thermal evaporation	Adhesive layer
23	ZnO	40	Spincoating	Buffer
24	ITO	120	Sputtering	Electrode

In **structure 2**, we implemented the following modifications: a buffer layer of ALD SnO₂ was added to enhance the protection of the red cell from the layers above. It was determined that using a conformal protection layer avoids the need for a dielectric layer, which, in turn, contributed to an increase in the EQE of the red cell. For the green cell, it was found that incorporating an AZO nanocrystal buffer layer significantly compromised the environmental stability of the sensors,

which would be crucial for further integration into CMOS as most of the conventional clean-room processes occur under ambient conditions. Furthermore, we removed dielectrics in the stack to minimize optical losses and simplify the fabrication.

The blue cell structure underwent a complete redesign, replacing the CsPbBr₂Cl uniform film with a gradient-grown film, utilizing the deposition of CsCl at a higher rate initially. These films exhibited a significantly higher EQE than those with uniform growth, enabling us to achieve a peak EQE of 54% in a top-illuminated structure. As for the ETL, a combination of C60/BCP/Ag/ZnO layers was found to outperform pure C60/ZnO, likely due to enhanced hole blocking and improved protection of the perovskite layer from sputter damage.

Supplementary Table 3. Comparative detectivity metrics of broadband perovskite, organic, silicon, and stacked perovskite photodetectors

Detector	D (Jones)	Reference			
Stacked - blue	2×10 ¹⁰	Our work			
Stacked - green	8.6×10 ¹⁰	Our work			
Stacked - red	1.5×10 ¹¹	Our work			
State-of-the-art l	broadband perovskite detector	rs			
PTAA/MAPbI ₃ /C ₆₀	7.8×10^{12}	2			
TiO ₂ /Al ₂ O ₃ /PCBM/MAPbI ₃ /Spiro/Au	4×10^{12}	3			
NiO _x :PbI ₂ /MAPbI ₃ /C ₆₀	4.0×10^{12}	4			
S	Silicon detectors				
FDS1010 (Thorlabs)	$4.8 \times 10^{12} \text{ at } 1 \text{cm}^2 \text{ (20 V)}$	5			
FDS100 (Thorlabs)	$3 \times 10^{13} \text{ at } 13 \text{ mm}^2 (5 \text{ V})$	5			
818-BB-45 (Hamamatsu)	1.1×10 ¹² at 1.1 mm ²	6			
Organic photodetectors					
PCDTBT:PC71BM	$1.8 \times 10^{12} (-1 \text{ V})$	7			
P3HT:PTB7: PC ₇₁ BM	$1.1 \times 10^{12} (0 \text{ V})$	8			
PBTTT:PC ₆₁ BM	$3.6 \times 10^{12} (0 \text{ V})$	9			
		1			

Supplementary Note 2. Alternative technologies promising for monolithic stacked detector fabrication

While perovskite absorber materials hold potential for monolithic stacked detector fabrication, it is important to note that this technology is not restricted to specific absorber materials. Any photosensitive materials possessing appropriate bandgap and transparency characteristics can

potentially serve as a viable option for color sensors. Alongside perovskite, we consider two classes of materials with tuneable bandgaps that hold promise for vertical stacking: III-V semiconductors and bulk heterojunction organic semiconductors. These material families have been extensively employed in tandem solar cells, which share a fundamentally similar architectural framework with stacked diode sensors. This note discusses existing technologies of III-V and organic semiconductors within the context of stacked detector applications.

2.1 III-V materials for integration in vertically stacked photodetectors.

Epitaxially grown III-V alloys offer superior optoelectronic materials characterized by a wide range of tunable bandgaps, as evidenced by numerous ultra-high-efficiency multijunction solar cells employed in concentrator and space applications ^{10,11}. Generally, the primary concern associated with III-V semiconductors is their cost, rendering them primarily suitable for niche applications that demand high performance and tolerate higher costs, such as space energy sources¹², ultra-high bandwidth detectors^{13,14}, and concentrator solar cells^{10,15,16}. Notably, recent advancements, particularly the adoption of an ultrasonic lift-off technique, have substantially mitigated costs by enabling substrate reuse, achieving a cost reduction of 4-6 times compared to traditional molecular beam epitaxy (MBE) growth techniques¹⁷. However, despite these cost reductions, lattice matching between film and substrate remains a critical factor in epitaxial growth processes, also influencing the performance of resulting devices^{10,11,18}. Here, we will address the primary III-V materials suitable for detecting colors within the visible spectrum, particularly those that align with the RGB color range. The summary of these findings is shown in Supplementary Table 4

2.1.1. Gallium-indium phosphide based materials

Ga_xIn_{1-x}P is utilized in the top and middle junction cells for terrestrial concentrator applications due to its tuneable bandgap ranging from approximately 1.68 to 1.93 eV^{18,19}. This range of bandgaps renders it suitable for use in red color detector pixels. The material is commonly employed as a top cell component in tandem multijunction cells yielding 47.6% efficient solar cells in 2022¹⁶. Typically, the growth of this material is confined to lattice-matching substrates such as GaAs wafers, as lattice mismatch can lead to a decrease in performance due to a high density of lattice dislocations at the interface with the substrate²⁰. It has been noted that obtaining

high-quality $Ga_xIn_{1-x}P$ is comparatively easier than $Al_xGa_{1-x}As$ due to the latter's strong affinity for the formation of Al-O defects during growth²¹.

Al_xGa_yIn_{1-x-y}P is employed in multijunction devices as a top cell component of tandem multijunction cells, typically grown directly on GaAs wafers or films interconnected via a tunnel junction, as reported in a recent paper highlighting solar cells with the second-highest performance at 47.1¹⁰ from NREL. If we extrapolate the geometry of this top-performing multijunction cell to the photodetector context, then the top two junctions, with bandgaps of 1.7 eV (Al_xGa_{1-x}As) and 2.1 eV, can potentially be utilized for red and green color detection, respectively, based on light absorption considerations.

However, the majority of reported phosphide and arsenide materials, which are direct bandgap semiconductors, typically have bandgaps reaching up to 2.38 eV, slightly below the approximately 2.5 eV bandgap²² required to maintain selectivity to blue light. Given that most absorbers in tandem solar cells do not utilize such wide bandgap materials, it becomes necessary to integrate a different material specifically tailored for blue light detection.

2.1.2. Gallium nitride and indium gallium nitride based materials

GaN-based nitride semiconductors have significantly advanced the development of optoelectronic devices, particularly laser diodes, LEDs, and UV photodetectors. The bandgap of gallium nitride (GaN) can be tuned by incorporating indium nitride (InN), resulting in the formation of InxGa₁. xN semiconductors. This modification allows for a variable bandgap that extends from 3.42 eV, characteristic of pure GaN, down to 1.7 eV. Furthermore, it is suggested that the bandgap could be reduced to as low as 0.64 eV with the use of pure InN^{23,24}. However, achieving uniform bandgap tunability is challenging due to the difference in lattice spacing between InN and GaN²⁵. The lattice mismatch between these materials presents obstacles in the growth of mixed In_xGa_{1-x}N films, although this challenge can be mitigated by utilizing GaN or AlN buffer layers as templates²⁶. Furthermore, InxGa₁-xN tends to exhibit n-type semiconductivity and must be doped to form p-n junctions for photodiodes. This process is hindered by the necessity to generate a high density of defects for p-doping to compensate for an excess of electrons in the material²⁷. Nonetheless, In_xGa_{1-x}N has emerged as a promising material for blue light detection in photodetectors ^{13,28,29}, and micro-detector arrays¹⁴, demonstrating high responsivity (.29 A/W at 400nm¹⁴) and low dark current detectors. Moreover, direct integration of In_xGa_{1-x}N on Si via a buffer GaN layer has been

demonstrated¹³. Additionally, there have been successful attempts towards integrating Al_xGa_yIn_{1-x-y}P and In_xGa_{1-x}N in dual-band LEDs, showcasing potential for their successful incorporation into multiband color detectors³⁰.

When it comes to detecting green light, it has been observed that as the band gap decreases, $In_xGa_{1-x}N$ experiences greater susceptibility to phase separation and high defect concentrations, resulting in poor color selectivity and increased leakage in devices 31 . Reports on green-light detection using $In_xGa_{1-x}N$ are scarce 31 , potentially due to its performance significantly lagging behind silicon performance with optical filters. Nevertheless, there are reports of existing multijunction solar cells employing $In_xGa_{1-x}N$ in conjunction with silicon, offering promise for the potential integration of this material as a middle layer in Si (red)/ $In_xGa_{1-x}N$ (green)/ $In_yGa_{1-y}N$ (blue) configurations 32 . However, thus far, only a 60% external quantum efficiency (EQE) has been demonstrated for $In_xGa_{1-x}N^{32}$, and research in this field remains relatively inactive.

2.1.3. Summary for III-V photodetectors

To sum up, a potentially viable sensor multistack comprising only III-V semiconductors as absorbers would entail lattice-matched Ga_xIn_{1-x}P or Al_xGa_{1-x}As for red and Al_xGa_yIn_{1-x-y}P for green detection layers, respectively, integrated with an In_xGa_{1-x}N layer via a GaN buffer layer. Achieving a sufficiently low degree of lattice mismatch between the nitride and phosphide/arsenide components would be crucial, possibly necessitating separate deposition of blue and R-G detectors and employing a lift-off transfer process for the former. However, even if successful, questions remain regarding how to pattern and make electrical contacts to this structure. For this purpose, one can deposit a transparent conductive oxide electrode, which, however, will interfere with the epitaxial growth of absorber layers on top of this layer. Alternatively, if heavily doped contacts are used, it is not apparent how feasible is to dope them and electrically separate them from the main stack to obtain a low-leakage device. Thus, the extremely intricate and costly fabrication procedure may be difficult to justify for commercial consumer-grade applications. Nevertheless, if successful transfer or growth of the blue cell onto a lattice-matched R-G cell with proper alignment, coupled with the successful implementation of contacts, is achieved, these detectors are anticipated to surpass perovskites in terms of both performance and stability.

Supplementary Table 4. Semiconductor compositions suitable for use in color detector layers amongst III-V semiconductors.

Composition	Target color	Band gap, eV	Substrate
Ga _x In _{x-1} P	R, G	1.83-1.93 ¹⁹ ,1.68-1.88 ¹⁸ ; 2.2-1.4 (pure InP) ³³	GaAs wafer ¹⁹
AlxGa1-xAs	R, G	1.42-2.16eV ³⁴	GaAs wafer ³⁴
AlxGayIn _{1-x-y} P	G	2.111	GaAs
AlxGa1-xP	R, G	2.33-1.4 ³³ ; 2.31 ³⁵	GaAs
InxGa1-xN	В	$2.8 - 1.7^{36}, 0.77 - 3.4^{25}, 3.5 - 1.7^{37}$	GaN, or GaN
			buffer

2.2 Organic photodetectors

In contrast to III-V semiconductors and perovskites, organic semiconductors have received much attention as highly suitable materials for vertically stacked color sensors, primarily due to their exceptional spectral tunability. This tunability is achievable through molecular engineering, facilitating the development of photodetectors that are inherently sensitive to various spectral regions. Additionally, organic photodetectors are attractive for their manufacturability using low-temperature, solution-based techniques, such as printing^{38,39} and spincoating^{40,41}, especially on flexible plastic substrates.

However, the fabrication of stacked organic photodetectors presents significant challenges. These include sputter damage incurred during the deposition of transparent conductive oxides⁴²⁻⁴⁴, and the requirement to select orthogonal solvent mixtures for the deposition of color-sensitive layers to prevent dissolution of underlying layers^{40,45,46}. In the case of thermally evaporated detectors, fabricating highly efficient devices poses significant challenges, primarily due to the inherent difficulties in forming bulk heterojunctions using a vapor deposition process^{47,48}. Moreover, there is a notable scarcity of high-performance blue light detectors in the literature⁴⁹.

Despite these challenges, there have been successful demonstrations of integrating organic semiconductors with silicon chips, ^{41,50-52} including the development of stacked organic sensors^{40,53-55}. There exist also reports about mechanically stacked triple-color organic detectors⁵⁶ of a single instance of a vertically stacked triple-color sensor using thin metal electrodes⁵⁷, likely utilised due to the technological difficulties associated with applying sputtered electrodes in organic photodetectors. This note seeks to evaluate these challenges and explore why a fully functional triple organic photodiode has yet to be reported, aiming to provide insights into the limitations and potential breakthroughs in this field.

2.2.1 Color selectivity of organic sensors

The color selectivity of organic sensors, particularly in the blue light spectrum, remains a challenging matter in the field of organic electronics. While numerous studies have focused on developing green⁵⁸⁻⁶⁰ and broadband^{8,61,62} organic detectors, the availability of organic materials suitable for blue light detection is comparatively limited. The most efficient blue detectors typically employ mixtures of C₆₀ or C₇₀ fullerene derivatives and donor molecules, such as rubrene^{49,63} or PffBT4T-2OD(Poly[(5,6-difluoro-2,1,3-benzothiadiazol-4,7-diyl)-alt-(3,3"'-di(2octyldodecyl)-2,2';5',2'';5'',2'''-quaterthiophen-5,5'''-diyl)]) ⁶⁴. However, the absorption spectrum of C60 does not align well with the blue spectral region, leading to suboptimal color selectivity in such devices. For instance, in stacked sensors with blue and green channels, a 20% response to green light (500-600nm) was observed from the blue channel, likely due to the optical absorbance from the PC₆₁BM ([6,6]-phenyl-C61-butyric acid methyl ester) layer⁴⁰. An alternative strategy involves the use of homojunctions with blue-sensitive chromophores. A notable example of color selective mechanically stacked 3-layer sensor used Co-TTP (tetraphenylporphyrin) which exhibits an absorption maximum at 430 nm. This peak, however, falls short of covering the entire visible blue region, leading to color selectivity that is inferior to that of modern color-filter arrays⁶⁵. Additionally, DPh-DNTT (diphenyl-dinaphtho[2,3-b:2',3'-f]-thieno[3,2-b] thiophene) has been explored for blue light sensitivity, aiming to minimize the blue cell's response to green and red light, with an absorption edge at around 520 nm⁵⁴. Despite these efforts, high levels of color crosstalk for blue light have been observed, attributed to the incomplete absorption by the bluesensitive layer. Other notable approaches have included the use of pure F8BT (poly(9,9-di-noctylfluorenyl-2,7-diyl)-co-1,4-benzo-(2,1,3)-thiadiazole) ⁶⁶ or F8BT doped with DMTPS (1,1dimethyl-2,3,4,5-tetraphenylsilole) ²⁵. Overall, aligning the absorption characteristics of organic materials with their electronic properties sufficient for high-performance detectors may not be as straightforward as with perovskites. This complexity suggests that challenges in developing stacked organic sensors, particularly those with precise color selectivity, may impede rapid progress in this area.

2.2.2 Transparent electrodes and sputter damage in organic photodetectors

Sputtering is a plasma-assisted, physical vapor deposition method that involves the bombardment of a target material by high energy ions followed by deposition of the ejected particles onto a substrate. The sputtering processes are widely used for the fabrication of transparent conductive oxide electrodes that possess superior transparency and stability compared to thin metal electrodes⁶⁷. However, a significant drawback of this technique is the sputtering damage inflicted on the underlying layers, attributable to the bombardment with highly energetic ions^{43,67,68}. This issue is of particular concern for organic semiconductors, which are vulnerable to oxygen and are physically soft, rendering them sensitive to such damage⁴³. As a result, many organic devices traditionally opt for metal or semitransparent metal electrodes, despite the compromise to the optical efficiency of stacked devices⁵⁷.

Recently, a growing interest is focused on semitransparent organic solar cells and photodetectors that incorporate transparent conductive oxides deposited atop the organic layer^{44,55}. This interest is likely spurred by advancements in tandem perovskite solar cells, which encounter similar challenges related to sputter damage^{69,70}. Additionally, less damaging transparent conductive oxide deposition methods can be used such as eclipse pulsed laser deposition, have demonstrated compatibility with organic solar cells (OSC), offering performance on par with metallic references ⁷¹. Nonetheless, these methods are often expensive and require sophisticated equipment.

2.2.3 Summary for organic photodetectors

Unlike perovskites, where bandgap tunability is achieved through halide mixing, tuning the bandgap in organic materials requires altering the molecular composition, which can impose significant challenges on the fabrication of multiband detectors. The limited availability of high-performance vapor-deposited organic photosensitive films necessitates reliance on solution-processed detectors, introducing challenges related to solvent compatibility between layers. Moreover, the broad absorption profile of organic detectors may not be as advantageous for machine vision applications when compared to perovskites, as discussed in Supplementary Note

3, suggesting no direct benefit in terms of color accuracy enhancement over existing color filter arrays. On the other hand, organic materials do not suffer from ion migration⁷², a significant concern for the stability of perovskite detectors. Despite the challenges, organic materials remain promising candidates for the development of stacked detectors, and their performance warrants comparison with perovskite technology as an alternative approach to multicolor pixel conception. Moreover, an important opportunity might arise from the monolithic integration of organic and perovskite layers in one archetecture, facilitated by the orthogonal solubility of perovskites and organic semiconductors in polar and non-polar solvents.

Supplementary Note 3. Procedure for evaluation of color accuracy of optical sensor

The color accuracy of the sensor has been tested under laboratory conditions that closely mimic the natural light reception process, allowing a quantitative evaluation. We used an optical stage (Fig. 3 a) where we positioned a light source, D50-equivalent with emission spectrum $W(\lambda)$ presented in Fig. 3 b (broadband white LED from LCFOCUS, FS-504, 10W, 380-780 nm), illuminating a translation stage with MacBeth ColorChecker with patches chart representing a standard color palette (the individual patches (m,n) are represented by albedo spectra $A_{m,n}(\lambda)$). The chart was masked with a black opaque stencil so that solely individual patches were illuminated. The reflected light is collimated and focused on the sample of perovskite stacked photodetectors. The photodetectors were operated under 0 V bias and the photocurrents from all 3 channels are measured. The color accuracy can be evaluated either through experimentally measured photocurrents or recalculated via measured EQE spectra. Both methods gave similar estimates. The latter method allows a direct comparison of the sensors of different technologies based on their spectral responsivity.

Theoretically, the values of the photocurrents (i=R, G, B) may be represented as:

$$P_{i,m,n} = \int_{380nm}^{800nm} W(\lambda) A_{m,n}(\lambda) \, \text{EQE}_{i}(\lambda) d\lambda$$
 (S1).

Alternatively, the photocurrent values are measured experimentally as presented in Fig. 3 a. The raw photocurrent values are corrected for background and cross-talk (10-15% for neighboring channels), normalized, linearized (corrected to the function $Argument^k$, where k = 0.4-0.6) or *i.e.* "grey-balanced" using 6 border patches with grey levels of the chart. To allocate the photocurrent signals (raw values of RGB channels) into a standard XYZ color space, they are to be renormalized with the transfer matrix:

$$X_{m.n} P_{R,m.n}$$

$$Y_{m.n} = M_{i,j} \cdot P_{G,m.n}$$

$$Z_{m.n} P_{B,m.n}$$
(S2)

where the transfer matrix $M_{i,j}$ is specific for a particular image sensor and is calculated as:

$$M_{i,j} = \int_{380nm}^{800nm} CIE_{XYZ_i}(\lambda) \, \text{EQE}_{j}(\lambda) d\lambda, \tag{S3}$$

where CIE_ XYZ_i are human standard observer functions with i=x,y,z and j=R,G,B channels of the sensor. For the correct calculation of the color accuracy the normalized XYZ values are transferred to CIELAB color space:

$$\varepsilon = 0.008856, \ \kappa = 903.3$$
 (S4)

$$fx = \begin{cases} \sqrt[3]{X} & \text{if } X > \varepsilon \\ \frac{\kappa X + 16}{116} & \text{otherwise} \end{cases}$$
 (S4)

$$fy = \begin{cases} \sqrt[3]{Y} & \text{if } Y > \varepsilon \\ \frac{\kappa Y + 16}{116} & \text{otherwise} \end{cases}$$
 (S5)

$$fz = \begin{cases} \sqrt[3]{Y} & \text{if } Y > \varepsilon \\ \frac{\kappa Y + 16}{116} & \text{otherwise} \end{cases}$$
 (S6)

$$L = 116fy - 16 (S7)$$

$$a = 500(fx - fy) \tag{S8}$$

$$b = 200(fy - fz) \tag{S9}$$

In the CIELAB color space color error or color difference is calculated as mean variation of the 3-color coordinated from the reference color coordinates *Lab*_ref for the corresponding color patch over the whole chart:

$$\Delta E_{Lab} = \sum_{m,n} \sqrt{\left(L_{m,n} - L_{ref_{m,n}}\right)^2 + \left(a_{m,n} - a_{ref_{m,n}}\right)^2 + \left(b_{m,n} - b_{ref_{m,n}}\right)^2} \quad (S10)$$

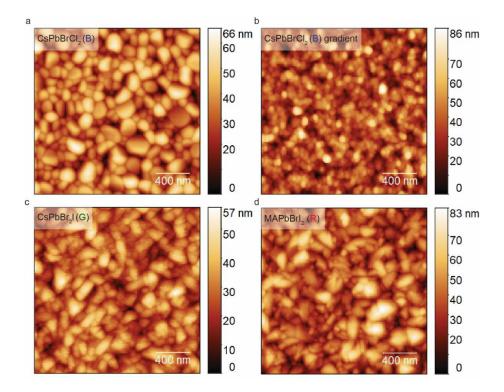
Apparently, as smaller the $\triangle Lab$ value for the particular color sensor are, the closer is the sensor to the ideal for color representation.

Finally, it is a good visual exercise to render back all the color values to the picture of the ColorChecker chart. Typically, it requires conversion of *XYZ* values to a standard *RGB* color space:

$$\begin{pmatrix} R \\ G \\ B \end{pmatrix} = M^{-1} \begin{pmatrix} X \\ Y \\ Z \end{pmatrix}, \quad \text{where } M = \begin{pmatrix} 0.412 & 0.358 & 0.18 \\ 0.213 & 0.715 & 0.072 \\ 0.019 & 0.119 & 0.950 \end{pmatrix}$$
(S11)

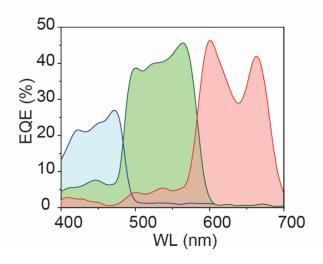
The comparison of the application of the above described algorithm for the sensor's sensitivity characteristics that correspond to Foveon, CFA, and stacked perovskite sensors is presented in

Extended Data Fig. 4. We note that the color representation, especially for Foveon-type sensors is far from adequate, so we suppose that commercial cameras utilize complicated proprietary postprocessing algorithms with "more aggressive" color cross-talk correction, use sensor-specific transfer matrises and gamma-corrections, etc.

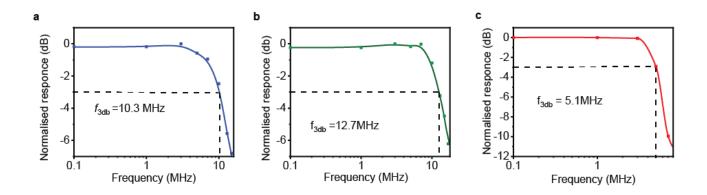


Supplementary Fig. 1 | Atomic force microscopy images of perovskite layers.

a, b CsPbBrCl₂ (B) **c.** CsPbBr₂I (G), **d**. MAPbBrI₂ (R), in normal and gradient configurations, were deposited on substrates that mimic the configuration of a single-color detector stack, specifically ITO/ETL for G detectors, or ITO/HTL for R and B detectors. Scans were collected in tapping mode in normal and gradient configurations were deposited on substrates that mimic the configuration of a single-color detector stack, specifically ITO/ETL for G detectors, or ITO/HTL for R and B detectors. Scans were collected in tapping mode.

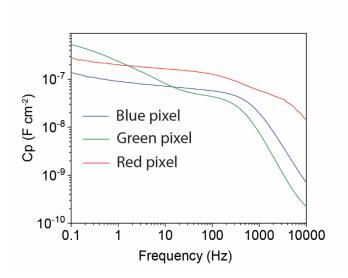


Supplementary Fig. 2 | External Quantum Efficiency of a stacked detector with structure 1. The 4-terminal structure contained CsPbBrCl₂ (B) CsPbBr₂I (G) MAPbBrI₂ (R) based detectors sandwiched between charge transport layers. R and G layers are separated with SnO₂/SiO₂ dielectric layer.

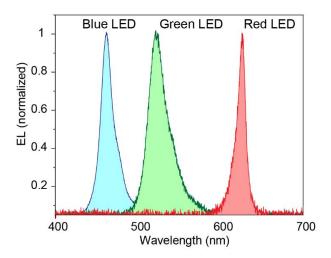


Supplementary Fig. 3 | 3 dB bandwidth of the R, G, and B single color detectors.

For these measurements, we fabricated smaller area (20x200µm) photodetectors to avoid RC-limited response. Additionally, we replaced the ITO layer with thin (30nm) gold. The detector responses were collected using a pico-second blue laser with a variable repetition rate.

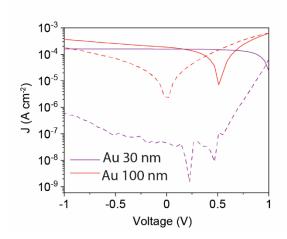


Supplementary Fig. 4 | Capacitance vs frequency measurements of stacked photodetectors. Capacitance was measured using impedance spectroscopy measurements and structure 1 pixel with 0.06 mm 2 (B) | 0.09 mm 2 (G) | 0.06 mm 2 (B) detector area. The measurements were done under dark conditions.



Supplementary Fig. 5 | Emission spectra of RGB channels emitted by LC-10W diode.

The data were experimentally measured utilizing a Thorlabs fiber optics spectrometer coupled via an optical fiber to the emitting surface of the LED.



Supplementary Fig. 6 | Comparative performance of red detectors with 30 nm and 100 nm bottom gold electrode. The J-V (current-voltage) performance curves presented are derived from samples with detector structures identical to those of the red detectors, arranged in a stacked configuration.

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